Hybrid 4z84 Traveler

January 21, 2000

1 Connectivity

Repairs on shorts:

Fixes for opens: Bus 3B, 2B jumped from chip 1 to chip 2, bus 7B jumped from chip 3 to chip 4

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 4Z84 has die: 193-106 193-107 193-109 193-111

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 4z84 classification info. Created 13:58:26 01/17/00

Hybrid 4z84 quality: fair
Chip classification: fair fair fair fair
Bad channels (chip-channel): 0-62 1-87 2-56 2-88 3-67
Bad cells: none
Random bad capacitors (chip-cell-channel): 2-13-85 2-14-88 2-15-91
   2-2-53 2-3-56
Channels at pedestal needed for DCMS: 31.8 30.3 33.7 31.2
```

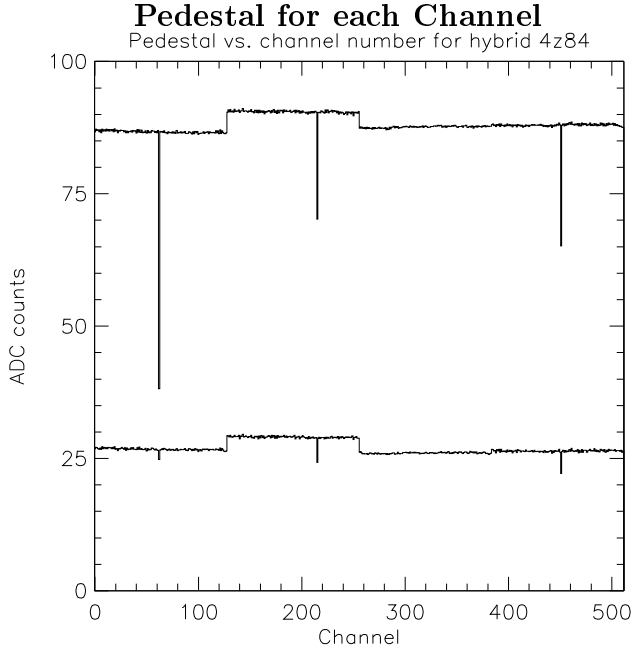
4 Comments

Encapsulated. FE DV finger gold bonds. HV tested.

5 Pedestal

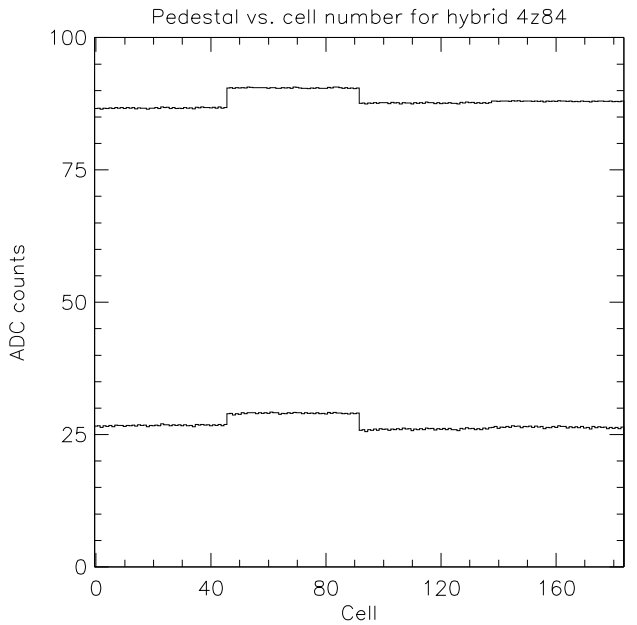
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

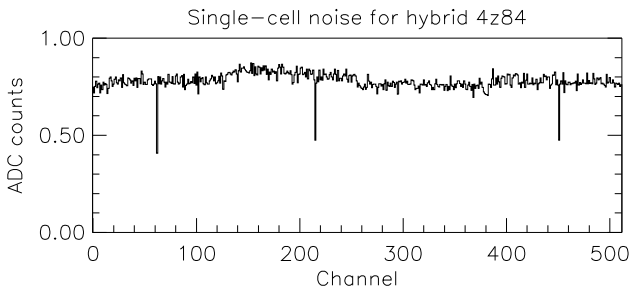
Pedestal vs. Pipeline Cell ID

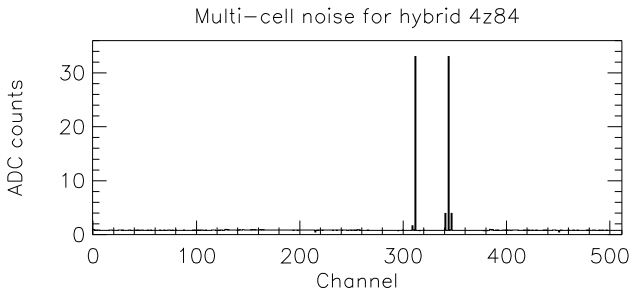


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

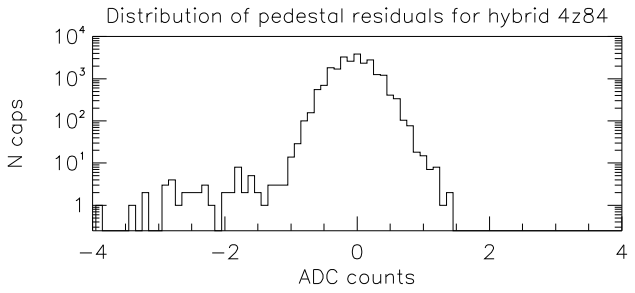
RMS Noise

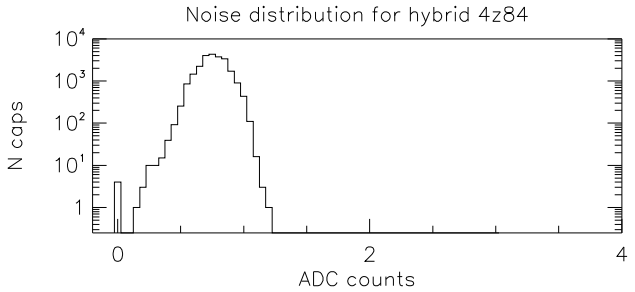




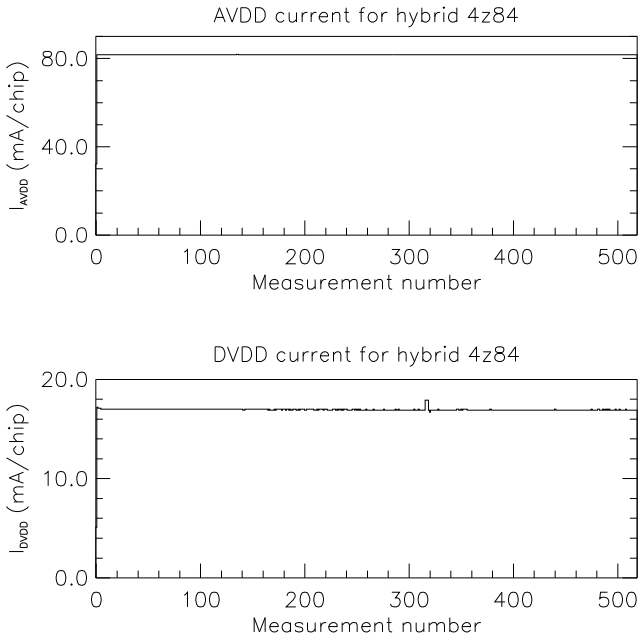
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in